

CORRECTION

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Correction: A dynamic sulfur-rich network from silicone industry waste

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Correction for 'A dynamic sulfur-rich network from silicone industry waste' by Zixiao Wang et al., *Green Chem.*, 2025, **27**, 13089–13098, <https://doi.org/10.1039/D5GC02864G>.

The authors regret that the scale bars in Fig. 4b and Fig. S18a were incorrect. The corrected Fig. 4 is shown here.
The supplementary information has also been updated to include a corrected version of Fig. S18.

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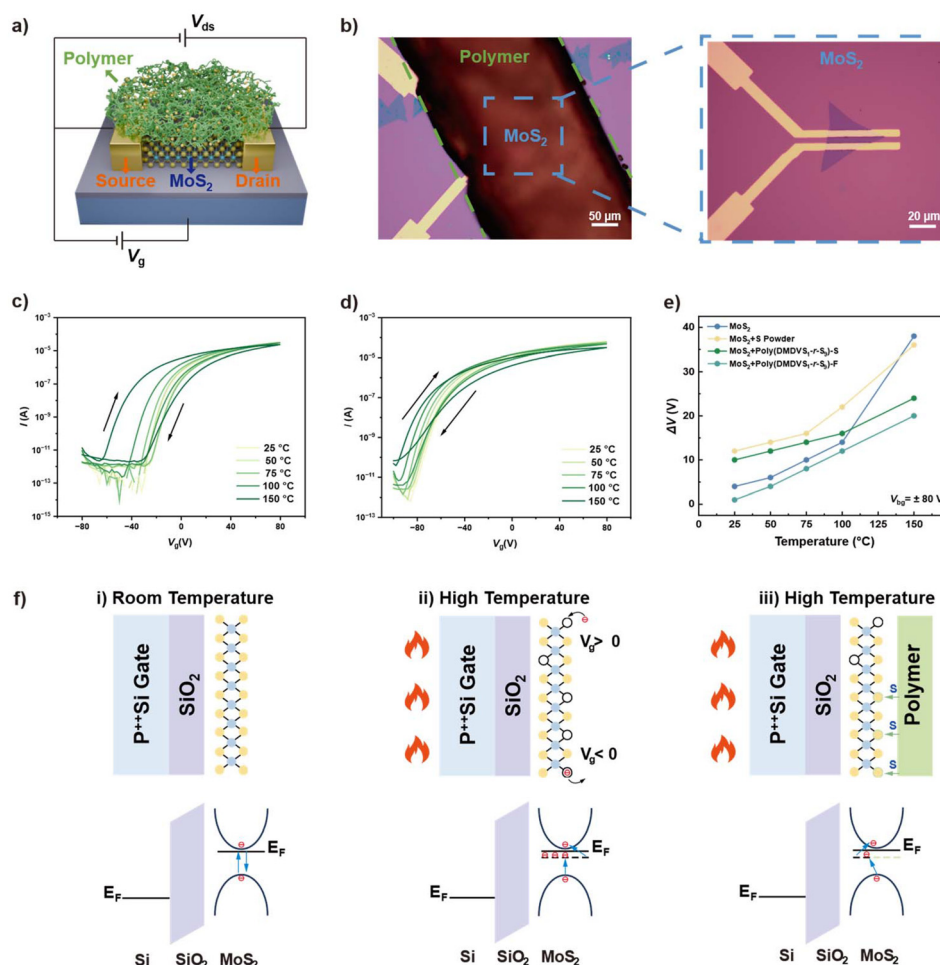


Fig. 4 Electrical characteristics of the MoS₂/poly(DMDVS₁-r-S₉)-F device. (a) Scheme and (b) optical micrograph of the MoS₂/poly(DMDVS₁-r-S₉)-F device. MoS₂ and poly(DMDVS₁-r-S₉)-F were outlined by the blue and green dashed lines, respectively. Transfer curves of the MoS₂ FETs (c) without and (d) with poly(DMDVS₁-r-S₉)-F measured across varying temperatures under vacuum. V_g from -100 to 80 V back and forth at $V_{ds} = 1$ V. (e) Extracted hysteresis window as a function of temperature incorporating various sulfur-containing materials. (f) Proposed mechanisms for hysteresis alongside the corresponding band diagrams: thermally activated SVs act as electron trapping/de-trapping centers in MoS₂, whereas sulfur moieties in the polymer partially passivate these SVs, thereby suppressing the hysteresis window at elevated temperatures.

The Royal Society of Chemistry apologises for these errors and any consequent inconvenience to authors and readers.

